

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	970	(703/14).CCLS.	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2006/04/19 12:02
L2	12453	((703/13-22) or (716/1-21)).CCLS.	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2006/04/19 12:03
L3	4621	(appl\$4 with stress) and ((calculat\$4 or comput\$4 and determin\$4) with stress)	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2006/04/19 12:04
L4	30	2 and 3	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2006/04/19 12:25

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L9	893	((Recogn\$4 or identif\$4 or determin\$4) with shape) and 2	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2006/04/19 14:01
L10	37	9 and ((determin\$4 or calculat\$4) with electrical with (parameter\$2 or characteristic\$2)) and extract\$4	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2006/04/19 14:03
L11	36	10 and (anal\$5 or simulat\$5)	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2006/04/19 14:04
L12	3	11 and ((appl\$4 or calculat\$5) with stress)	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2006/04/19 14:04

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S1	506	(mask adj layout) and (design\$4 with circuit) and simulat\$6 and semiconductor	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2006/04/19 12:02
S2	38	S1 and ((determin\$5 or obtain\$4 or calculat\$4) with electrical)	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2006/02/08 14:50
S3	5	S2 and ((recogniz\$4 or identif\$5) with (shape or model))	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2006/02/08 14:51